


<b>Search Notes</b> 	<b>Application/Control No.</b> 10584634	<b>Applicant(s)/Patent Under Reexamination</b> IKEDA ET AL.
	<b>Examiner</b> Sophie Hon	<b>Art Unit</b> 1783

SEARCHED			
Class	Subclass	Date	Examiner
428	1.3,1.32-1.33	6/22/10	SH
349	137	"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search attached	6/22/10	SH
Reviewed STIC EIC Search by searcher Huang, Mei Q. dated 9/26/08	"	"
Reviewed correlated appln 11/886,258	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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